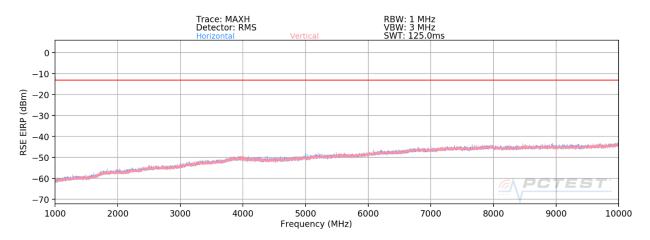


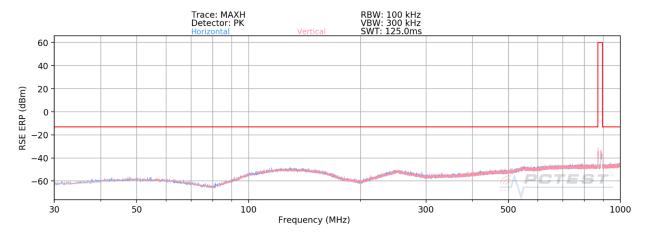
Plot 7-913. Radiated spurious emission_30 MHz to 1000 MHz (DSS_B5_10M+10M_2C_Mid Channel)



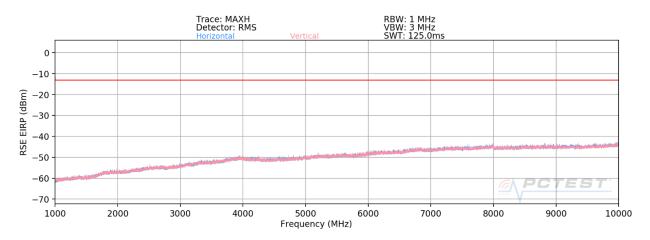
Plot 7-914. Radiated spurious emission_1 GHz to 10 GHz (DSS_B5_10M+10M_2C)_Mid Channel)

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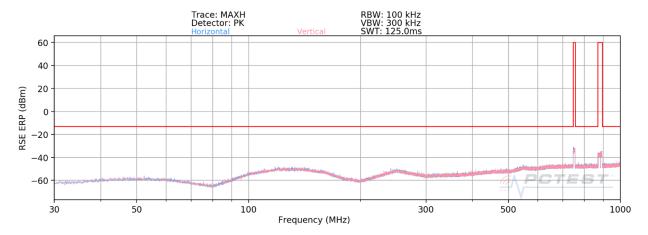
Plot 7-915. Radiated spurious emission_30 MHz to 1000 MHz (DSS_B5_10M+10M+5M_3C_Mid Channel)



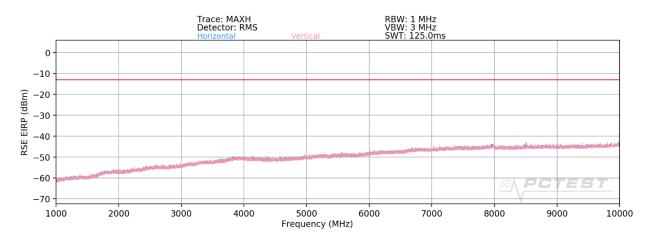
Plot 7-916. Radiated spurious emission_1 GHz to 10 GHz (DSS_B5_10M+10M+5M_3C_Mid Channel)

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Plot 7-917. Radiated spurious emission_30 MHz to 1000 MHz (Multi Band_DSS_B5_5M+10M+10M_3C + B13_5M+5M_2C_Low Channel)



Plot 7-918. Radiated spurious emission_1 GHz to 10 GHz (Multi Band_DSS_B5_5M+10M+10M_3C + B13_5M+5M_2C_Low Channel)

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Bandwidth (MHz):	B5_5MHz + B13_5MHz
Frequency (MHz):	1 st Carrier : B5_891.5 2 st Carrier : B13_748.5
Modulation Signal:	QPSK

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Heigh [cm]	Turntable azimuth [degree]	Analyzer Level [dBm]	AFCL [dBm]	Field Stength [dB W/m]	RSE EIRP [dBm]	Limit [dBm]	Margin [dB]
975.16	Н	155	10	-82.04	25.89	50.85	-44.41	-13.00	-31.41
976.85	V	250	355	-82.06	25.90	50.84	-44.42	-13.00	-31.42
9516.74	Н	150	5	-81.04	21.08	47.03	-48.22	-13.00	-35.22
9508.45	V	180	45	-81.06	20.95	46.90	-48.36	-13.00	-35.36

Table 7-247. Radiated transmitter Emission Table (Multi Band_B5_5M_1C_Low + B13_5M_1C_High)

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7.8 Frequency Stability / Temperature Variation §2.1055

Test Overview and Limit

Frequency stability testing is performed in accordance with the guidelines of ANSI C63.26-2015. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Test Procedure Used

ANSI C63.26-2015 - Section 5.6

Test Settings

- 1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Test Setup

The EUT was connected via an RF cable to a spectrum analyzer with the EUT placed inside an environmental chamber.

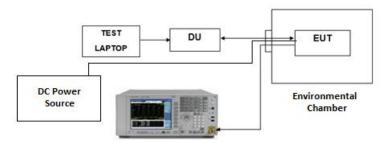


Figure 7-9. Test Instrument & Measurement Setup

Test Notes

None

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Band 5 Frequency Stability Measurements

OPERATING FREQUENCY: 881,500,000 Hz REFERENCE VOLTAGE: -48.00 **VDC**

VOLTAGE	POWER	TEMP	FREQUENCY	Freq. Dev.	Deviation
(%)	(VDC)	(°C)	(Hz)	(Hz)	(%)
100 %		+ 20 (Ref)	881,500,017.001	0.00	0.0000000
100 %		- 30	881,500,011.384	-5.62	-0.0000006
100 %		- 20	881,500,013.728	-3.27	-0.0000004
100 %		- 10	881,500,017.711	0.71	0.000001
100 %	-48	0	881,500,010.893	-6.11	-0.0000007
100 %	-40	+ 10	881,500,014.474	-2.53	-0.0000003
100 %		+ 20	881,500,017.001	0.00	0.0000000
100 %		+ 30	881,500,007.788	-9.21	-0.0000010
100 %		+ 40	881,500,014.113	-2.89	-0.0000003
100 %		+ 50	881,500,011.237	-5.76	-0.0000007
85 %	-40.80	+ 20	881,500,007.952	-9.05	-0.0000010
115 %	-55.20	+ 20	881,500,016.687	-0.31	0.0000000

Table 7-248. Frequency Stability Data

Note:

Based on the results of the frequency stability test at the center channel the frequency deviation results measured are very small. As such it is determined that the channels at the band edge would remain in-band when the maximum measured frequency deviation noted during the frequency stability tests is applied. Therefore the device is determined to remain operating in band over the temperature and voltage range as tested.

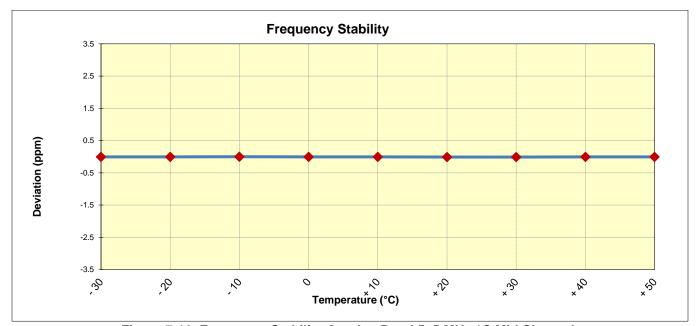


Figure 7-10. Frequency Stability Graph - Band 5_5 MHz 1C Mid Channel

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Band 13 Frequency Stability Measurements

OPERATING FREQUENCY: 751,000,000 Hz REFERENCE VOLTAGE: -48.00 **VDC**

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %		+ 20 (Ref)	751,000,014.128	0.00	0.0000000
100 %		- 30	751,000,012.965	-1.16	-0.0000002
100 %		- 20	751,000,007.919	-6.21	-0.0000008
100 %		- 10	751,000,010.742	-3.39	-0.0000005
100 %	-48	0	751,000,013.582	-0.55	-0.000001
100 %	-40	+ 10	751,000,014.606	0.48	0.000001
100 %		+ 20	751,000,014.128	0.00	0.0000000
100 %		+ 30	751,000,015.007	0.88	0.000001
100 %	- -	+ 40	751,000,009.695	-4.43	-0.0000006
100 %		+ 50	751,000,012.405	-1.72	-0.0000002
85 %	-40.80	+ 20	751,000,014.335	0.21	0.0000000
115 %	-55.20	+ 20	751,000,007.105	-7.02	-0.0000009

Table 7-249. Frequency Stability Data

Note:

Based on the results of the frequency stability test at the center channel the frequency deviation results measured are very small. As such it is determined that the channels at the band edge would remain in-band when the maximum measured frequency deviation noted during the frequency stability tests is applied. Therefore the device is determined to remain operating in band over the temperature and voltage range as tested.

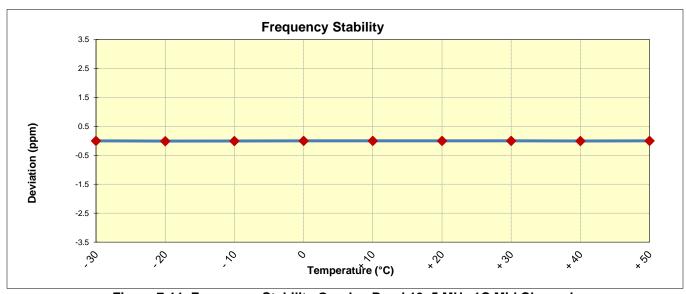


Figure 7-11. Frequency Stability Graph - Band 13_5 MHz 1C Mid Channel

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CONCLUSION 8.0

The data collected relate only to the item(s) tested and show that the Samsung RRU (RF4440d)

FCC: A3LRF4440D-13A complies with all of the requirements of Part22 and 27 of the FCC Rules.

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